

## Description

The Si2307CDS-T1-GE3 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

## **General Features**

 $V_{DS} = -30V, I_D = -4.1A$  $R_{DS(ON)} < 56m\Omega @ V_{GS} = 10V$ 

## Application

High power and current handing capability Lead free product is acquired Surface mount package PWM applications Load switch Power management

## Package Marking and Ordering Information

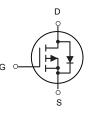
Product ID	Pack	Brand	Qty(PCS)
Si2307CDS-T1-GE3	SOT-23	HXY MOSFET	3000

## Absolute Maximum Ratings (T<sub>A</sub>=25<sup>°</sup>C unless otherwise noted)

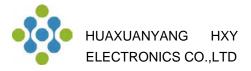
Symbol	Parameter	Limit	Unit
Vds	Drain-Source Voltage	-30	V
V <sub>GS</sub>	Gate-Source Voltage	±20	V
lo	Drain Current-Continuous	-4.1	A
Ом	Drain Current-Pulsed (Note 1)	-13	A
PD	Maximum Power Dissipation	1.32	W
TJ,TSTG	Operating Junction and Storage Temperature Range	-55 To 150	°C
Reja	Thermal Resistance, Junction-to-Ambient (Note 2)	125	°C/W







P-Channel MOSFET



# Si2307CDS-T1-GE3

P-Channel Enhancement Mode MOSFET

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-30			V
∆BV <sub>DSS</sub> /∆T <sub>J</sub>	BVDSS Temperature Coefficient	Reference to 25℃ , I <sub>D</sub> =-1mA		-0.02		V/°C
D	Statia Drain Courses On Desistance <sup>2</sup>	V <sub>GS</sub> =-10V , I <sub>D</sub> =-3A	48 56		56	
Rds(on)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-1.5A		78	90	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage		-1.2	-1.5	-2.5	V
$ riangle V_{GS(th)}$	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA			4.32		mV/°C
1	Drain-Source Leakage Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			-1	- uA
I <sub>DSS</sub>		V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			-5	
Igss	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-3A		4.8		S
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		24	48	Ω
Qg	Total Gate Charge (-4.5V)			5.22	7.3	
Qgs	Gate-Source Charge	V <sub>DS</sub> =-20V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-3A		1.25	1.8	nC
$Q_gd$	Gate-Drain Charge			2.3	3.2	
T <sub>d(on)</sub>	Turn-On Delay Time			18.4	37	
Tr	Rise Time	$V_{DD}$ =-15V , $V_{GS}$ =-10V , $R_{G}$ =3.3 $\Omega$		11.4	21	
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =-1A		39.4	79	ns
T <sub>f</sub>	Fall Time			5.2	10.4	
Ciss	Input Capacitance			463	650	pF
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , f=1MHz		82	115	
Crss	Reverse Transfer Capacitance	ance		68	95	
ls	Continuous Source Current <sup>1,4</sup>				-3.2	Α
lsм	Pulsed Source Current <sup>2,4</sup>	──V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-13	А
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			-1	V

#### Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width  $\,\leq\,$  300us , duty cycle  $\,\leq\,$  2%

3. The power dissipation is limited by 150°C junction temperature

4.The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications , should be limited by total power dissipation.



# Si2307CDS-T1-GE3 P-Channel Enhancement Mode MOSFET

#### **Typical Characteristics**

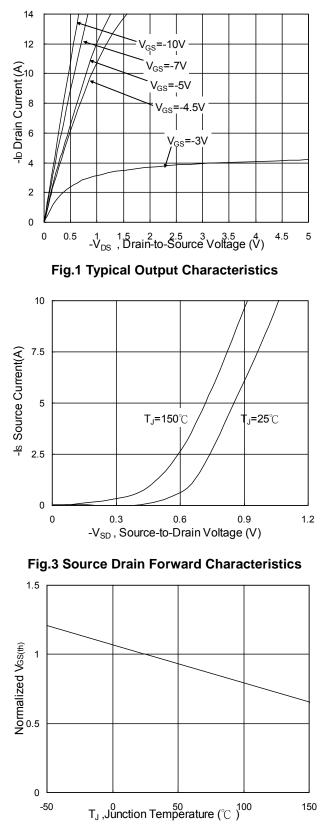


Fig.5 Normalized V<sub>GS(th)</sub> vs. T<sub>J</sub>

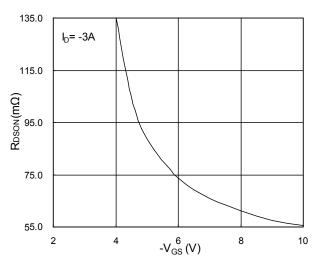


Fig.2 On-Resistance vs. G-S Voltage

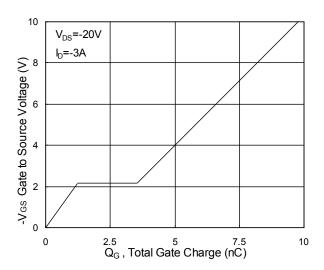


Fig.4 Gate-Charge Characteristics

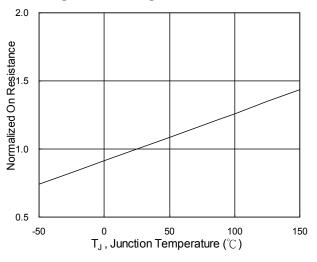
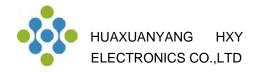


Fig.6 Normalized RDSON vs. TJ



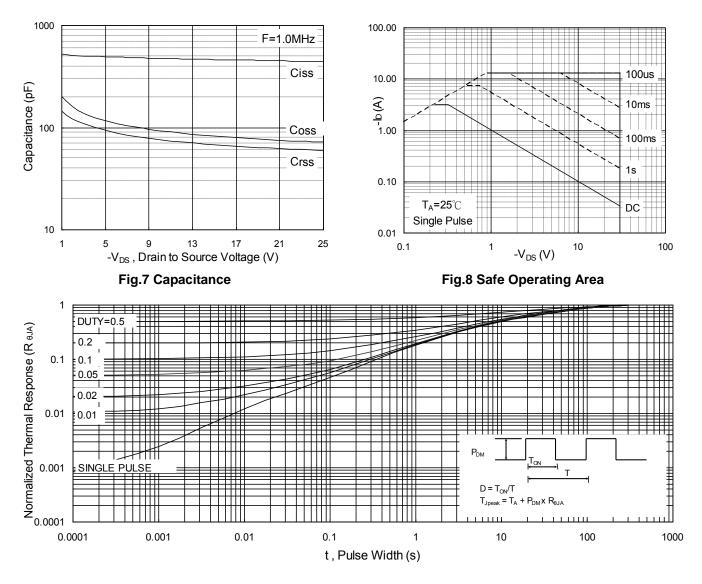


Fig.9 Normalized Maximum Transient Thermal Impedance

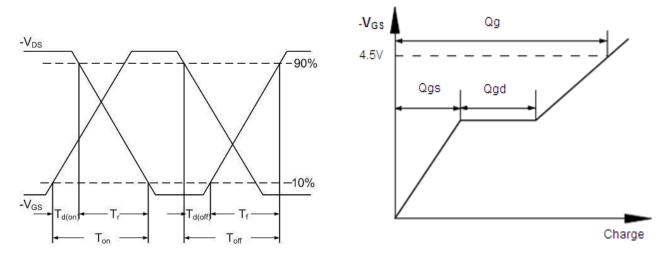
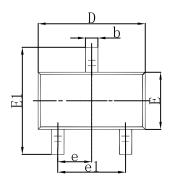


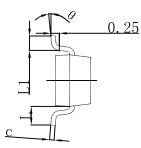
Fig.10 Switching Time Waveform

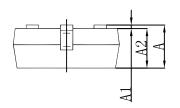
Fig.11 Gate Charge Waveform



## **SOT-23 Package Outline Dimensions**

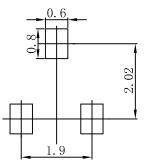






Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
E	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.037 TYP		
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022 REF		
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

# SOT-23 Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters.

2.General tolerance:± 0.05mm.
 3.The pad layout is for reference purposes only.



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